

Softshell Pin & Socket Contacts
1. PURPOSE

The purpose of this test is to verify resistance after extended durability cycles.

2. RESULTS

The following resistance results were collected after the specimens were subjected to the specified durability cycles. 6.25 inches of 20 AWG wire was subtracted out of the original values as specified in the test request.

Test Sequence	Requirement	Results In Milliohms			Data Points
		Min	Max	ΔMax	
Test Group 1 (Tin)					
Initial	No initial resistance requirement	1.33	1.47	---	36
After 25 cycles	Δ change shall not exceed 10 milliohms	1.39	1.52	.14	36
After 50 cycles	Δ change shall not exceed 10 milliohms	1.43	1.57	.16	36
After 100 cycles	Δ change shall not exceed 10 milliohms	1.46	1.60	.22	36
Test Group 2 (Tin)					
Initial	No initial resistance requirement	2.71	3.00	---	36
After 25 cycles	Δ change shall not exceed 10 milliohms	2.77	3.33	.55	36
After 50 cycles	Δ change shall not exceed 10 milliohms	2.84	3.71	.93	36
After 100 cycles	Δ change shall not exceed 10 milliohms	2.95	5.40	2.53	36
Test Group 3 (Tin)					
Initial	No initial resistance requirement	2.58	2.90	---	35
After 25 cycles	Δ change shall not exceed 10 milliohms	2.69	3.17	.51	35
After 50 cycles	Δ change shall not exceed 10 milliohms	2.75	3.46	.70	35
After 100 cycles	Δ change shall not exceed 10 milliohms	2.73	4.11	1.39	35
Test Group 4 (Gold)					
Initial	No initial resistance requirement	1.53	1.69	---	36
After 25 cycles	Δ change shall not exceed 10 milliohms	1.62	1.91	.25	36
After 50 cycles	Δ change shall not exceed 10 milliohms	1.67	2.25	.59	36
After 100 cycles	Δ change shall not exceed 10 milliohms	1.65	2.15	.50	36
After 150 cycles	Δ change shall not exceed 10 milliohms	1.69	3.25	1.68	36
After 200 cycles	Δ change shall not exceed 10 milliohms	1.72	2.81	1.16	36
Test Group 5 (Gold)					
Initial	No initial resistance requirement	2.73	3.01	---	30
After 25 cycles	Δ change shall not exceed 10 milliohms	2.77	3.27	.39	30
After 50 cycles	Δ change shall not exceed 10 milliohms	2.77	3.04	.18	30
After 100 cycles	Δ change shall not exceed 10 milliohms	2.80	3.12	.27	30
After 150 cycles	Δ change shall not exceed 10 milliohms	2.84	3.22	.33	30
After 200 cycles	Δ change shall not exceed 10 milliohms	2.86	3.20	.38	30

Figure 1 (cont)

Test Sequence	Requirement	Results In Milliohms			Data Points
		Min	Max	ΔMax	
Test Group 6 (Gold)					
Initial	No initial resistance requirement	2.65	3.13	---	32
After 25 cycles	Δ change shall not exceed 10 milliohms	2.69	3.01	.25	32
After 50 cycles	Δ change shall not exceed 10 milliohms	2.73	3.07	.30	32
After 100 cycles	Δ change shall not exceed 10 milliohms	2.61	3.61	.91	32
After 150 cycles	Δ change shall not exceed 10 milliohms	2.76	3.55	.85	32
After 200 cycles	Δ change shall not exceed 10 milliohms	2.69	3.44	.74	32

Figure 1 (end)

3. SPECIMEN DESCRIPTION

Test Group	Part Number	Revision	Description
1	350218-1	BP	UMNL pin with 20 AWG wire
	350536-1	BB	UMNL socket with 20 AWG wire
	1-480704-0	BR	UMNL plugs
	1-480705-0	BN	UMNL caps
2	770903-1	H	Mini UMNL pin with 20 AWG wire
	770904-1	J	Mini UMNL socket with 20 AWG wire
	1-480704-0	BR	UMNL plugs
	1-480705-0	BN	UMNL caps
3	794220-1	G	Mini 2 pin with 20 AWG wire
	794221-1	G	Mini 2 socket with 20 AWG wire
	172161-1	K	Mini UMNL caps
	172169-1	J	Mini UMNL plugs
4	350218-2	BP	UMNL pin (gold) with 20 AWG wire
	350536-2	BB	UMNL socket (gold) with 20 AWG wire
	172161-1	K	Mini UMNL caps
	172169-1	J	Mini UMNL plugs
5	770903-3	H	Mini UMNL pin (gold) with 20 AWG wire
	770904-3	J	Mini UMNL socket (gold) with 20 AWG wire
	172161-1	K	Mini UMNL caps
	172169-1	J	Mini UMNL plugs
6	794220-3	G	Mini 2 pin (gold) with 20 AWG wire
	794221-3	G	Mini 2 socket (gold) with 20 AWG wire
	172161-1	K	Mini UMNL caps
	172169-1	J	Mini UMNL plugs

NOTE

Per the requester, UMNL plugs (PN 1-480704-0) and UMNL caps (PN 1-480705-0) were used for Test Groups 1 and 2; Mini UMNL caps (PN 172161-1) and Mini UMNL plugs (PN 172169-1) were used with Test Groups 3, 4, 5 and 6.

Figure 2

4. SPECIMEN PREPARATION

All contacts were crimped onto 20 AWG wire prior to being submitted for testing. The 20 AWG wires were measured to 6.25 inches from the back of the crimp, cut, stripped and tinned to achieve 6 inches of insulation. The 20 AWG wires were then soldered onto printed circuit board PN 93-660001, Revision B. Pins and sockets were mated and all solder joints were inspected.

5. TEST PROCEDURES**5.1. Termination Resistance**

Termination resistance was performed per AMP Specification 109-6-6, Revision J. All mated test specimens were subjected to 20 millivolts maximum open circuit voltage at 100 milliamperes. Measurements were taken using a 4 wire scan method. A system standard was read to verify that the system was functioning properly.

5.2. Durability

Durability was performed per AMP Specification 109-27, Revision D. All tin plated specimens were subjected to 100 manual mating and unmating cycles. Termination resistance readings were taken initially, and after 25, 50, and 100 cycles. The gold specimens were subjected to a total of 200 manual cycles. Termination resistance readings were taken initially, and after 25, 50, 100, 150, and 200 cycles.

6. TEST EQUIPMENT

Description	Manufacturer	Model Number	Calibration Number
R2 Data Acquisition System	Hewlett-Packard	3456A	E2997-0171
B1 Data Acquisition System	Hewlett-Packard	3456A	E2997-0170
R1 Data Acquisition System	Hewlett-Packard	3456A	E2997-0131